

# 2SD1773

## Silicon NPN triple diffusion planar type darlington

For midium speed switching

Complementary to 2SB1193

### ■ Features

- High forward current transfer ratio  $h_{FE}$
- High-speed switching
- Full-pack package which can be installed to the heat sink with one screw

### ■ Absolute Maximum Ratings $T_C = 25^\circ\text{C}$

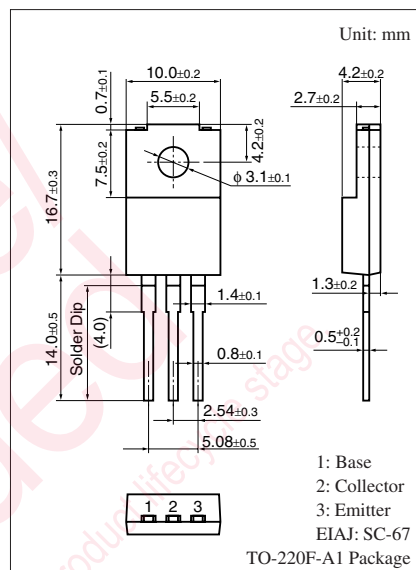
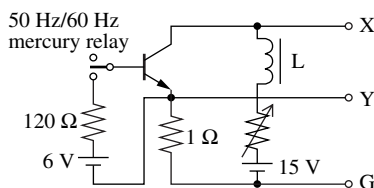
Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	$V_{CBO}$	120	V
Collector-emitter voltage (Base open)	$V_{CEO}$	120	V
Emitter-base voltage (Collector open)	$V_{EBO}$	7	V
Collector current	$I_C$	8	A
Peak collector current	$I_{CP}$	12	A
Collector power dissipation	$P_C$	50	W
	$T_a = 25^\circ\text{C}$	2.0	
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

### ■ Electrical Characteristics $T_C = 25^\circ\text{C} \pm 3^\circ\text{C}$

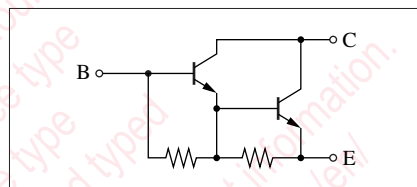
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-emitter sustaining voltage *	$V_{CEO(SUS)}$	$I_C = 2\text{ A}, R_{BE} = \infty, L = 10\text{ mH}$	120			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_E = 50\text{ mA}, I_C = 0$	7			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 120\text{ V}, I_E = 0$			100	$\mu\text{A}$
Collector-emitter cutoff current (Base open)	$I_{CEO}$	$V_{CE} = 100\text{ V}, R_{BE} = \infty$			10	$\mu\text{A}$
Forward current transfer ratio	$h_{FE}$	$V_{CE} = 3\text{ V}, I_C = 4\text{ A}$	1000		20000	—
Collector-emitter saturation voltage	$V_{CE(sat)1}$	$I_C = 4\text{ A}, I_B = 8\text{ mA}$			1.5	V
	$V_{CE(sat)2}$	$I_C = 8\text{ A}, I_B = 80\text{ mA}$			3.0	
Base-emitter saturation voltage	$V_{BE(sat)1}$	$I_C = 4\text{ A}, I_B = 8\text{ mA}$			2.0	V
	$V_{BE(sat)2}$	$I_C = 8\text{ A}, I_B = 80\text{ mA}$			3.5	
Transition frequency	$f_T$	$V_{CE} = 10\text{ V}, I_C = 1\text{ A}, f = 1\text{ MHz}$		20		MHz
Turn-on time	$t_{on}$	$I_C = 4\text{ A}, I_{B1} = 8\text{ mA}, I_{B2} = -8\text{ mA}$		0.7		$\mu\text{s}$
Storage time	$t_{stg}$	$V_{CC} = 50\text{ V}$		6.0		$\mu\text{s}$
Fall time	$t_f$			2.0		$\mu\text{s}$

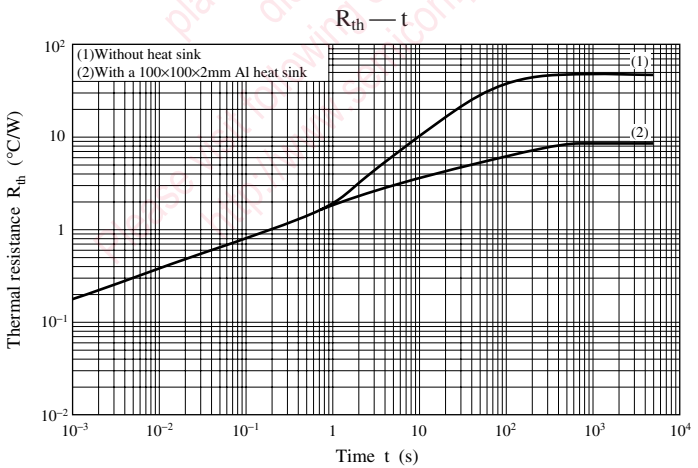
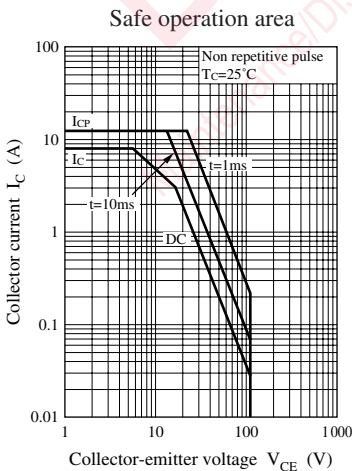
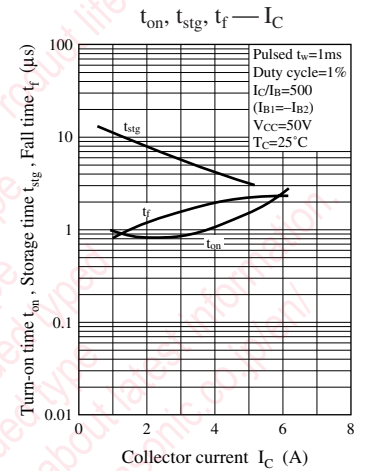
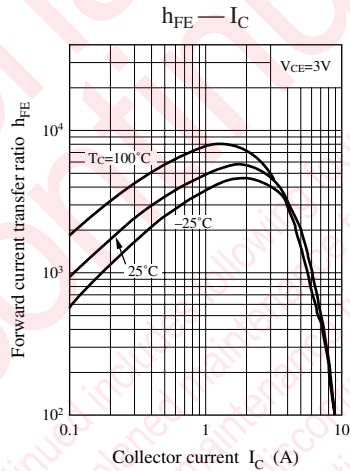
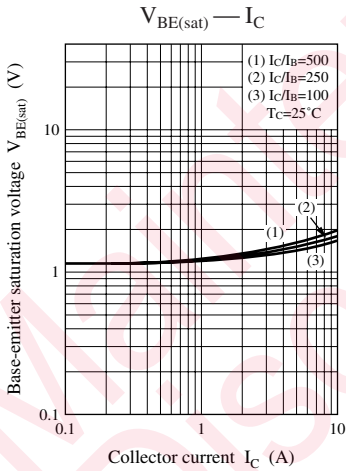
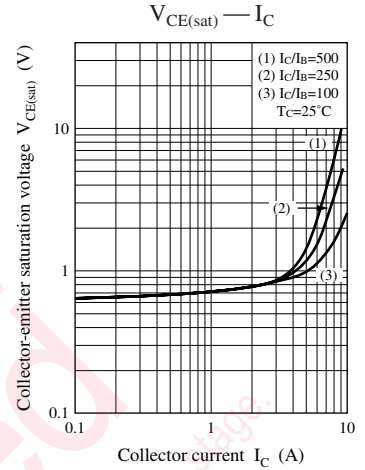
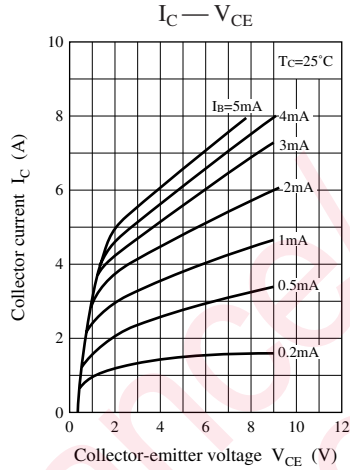
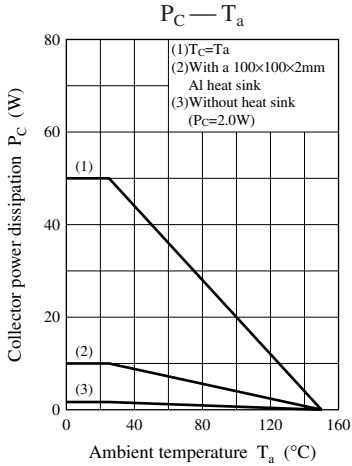
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*:  $V_{CEO(SUS)}$  Test circuit



### Internal Connection





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